

TMS570LC4357 and RM57L843 On-Chip Temperature Sensor Measurements

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ABSTRACT

This application report demonstrates how to use the on-chip temperature sensors for junction temperature monitoring. Junction temperature monitoring is the only recommended use for these on-chip temperature sensors.

Project collateral and source code discussed in this application report were generated with HalCoGen 4.05.01 for the [TMS570LC43x launchpad](#) and can be downloaded from the following URL: <http://www.ti.com/lit/zip/spna216>.

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1 Introduction

The [TMS570LC4357](#) and [RM57L843](#) have three on-chip temperature sensors for monitoring the junction temperature, allowing the application to pro-actively manage device utilization so as not to violate the maximum junction temperature specification.

The measurements of the three on-die temperature sensors are routed to a MibADC for conversion into digital values. The CPU can read out the digital values and compare with the calibrated temperature value stored in the device's one-time programmable memory (OTP). If the measured temperature exceeds the specification, the application can choose to take actions such as log the event or reduce the junction temperature by turning off peripherals or slowing down some clocks.

2 Temperature Sensor Information

2.1 Sensor Connection

There are three instances of temperature sensors in the device. The temperature sensors are connected to a on-chip analog-to-digital converter (ADC) through the Input/Output Multiplexing Module (IOMM). Temperature sensor 1 is multiplexed with AD1IN[31]. Temperature sensor 2 is connected to AD2 channel 31. Temperature sensor 3 is connected to AD2 channel 30. By default, the three temperature sensors are disabled. The three temperature sensors are enabled by clearing PINMMR174[24] to low. By default pin multiplexing is locked and can be unlocked by writing the unlock values to the kicker0 and kicker1 registers as demonstrated in the example code.

Table 1. Temperature Sensor Selection

Decode ⁽¹⁾	Select
AD1CHNSEL(31) = 1 PINMMR173(16) = 0 PINMMR173(17) = 1	Temp Sensor 1
AD1CHNSEL(31) = 1 PINMMR173(16) = 1 PINMMR173(17) = 0	ADC1IN[31]
AD2CHNSEL(31) = 1 PINMMR173(24) = 0 PINMMR173(25) = 1	Temp Sensor 2
AD2CHNSEL(31) = 1 PINMMR173(24) = 1 PINMMR173(25) = 0	No Connection
AD2CHNSEL(30) = 1 PINMMR174(0) = 0 PINMMR174(1) = 1	Temp Sensor 3
AD2CHNSEL(30) = 1 PINMMR174(0) = 1 PINMMR174(1) = 0	No Connection

⁽¹⁾ AD1CHNSEL is configured inside the MibADC1 module. AD2CHNSEL is configured inside the MibADC2 module.

2.2 Temperature Sensor Location

Temperature sensors 1 and 2 are near the ADCs, opposite the pin A1 corner. Temperature sensor 3 is near the center of the device. In this example, the three sensors gave close to the same results. This is as expected because the thermal conductivity of silicon is high.

2.3 Temperature Sensor Calibration

The temperature sensors are designed to be used with software calibration. To support software calibration of the temperature sensors, TI has recorded the value returned by recording the reading of each sensor at different junction temperatures. The measurements were done while the device is still in wafer form and the junction temperature can be well controlled by the wafer prober. The values are recorded in the TI OTP starting at location F008 0310h as shown in [Figure 1](#) and described in [Table 2](#). The values recorded were measured with ADREFHI equal to 3.30 V. It is important to have ADREFHI at 3.30V and ADREFLO at 0V, or to adjust the results from reading the temp sensor to compensate for the difference. A difference on ADREF of 5% can result in the calculations being off by 22°C at 125°C junction temperature.

Figure 1. TI OTP Bank 0 Temperature Sensor 1 Calibration Information (F008 0310h-F008 031Fh)

0x00		0x04		0x08		0x0C	
S1TEMP1VAL	S1TEMP1	S1TEMP2VAL	S1TEMP2	S1TEMP3VAL	S1TEMP3	0xFFFF	0xFFFF
R	R	R	R	R	R	R	R

LEGEND: R = Read only

Figure 2. TI OTP Bank 0 Temperature Sensor 2 Calibration Information (F008 0320h-F008 032Fh)

0x00		0x04		0x08		0x0C	
S2TEMP1VAL	S2TEMP1	S2TEMP2VAL	S2TEMP2	S2TEMP3VAL	S2TEMP3	0xFFFF	0xFFFF
R	R	R	R	R	R	R	R

LEGEND: R = Read only

Figure 3. TI OTP Bank 0 Temperature Sensor 3 Calibration Information (F008 0330h-F008 033Fh)

0x00		0x04		0x08		0x0C	
S3TEMP1VAL	S3TEMP1	S3TEMP2VAL	S3TEMP2	S3TEMP3VAL	S3TEMP3	0xFFFF	0xFFFF
R	R	R	R	R	R	R	R

LEGEND: R = Read only

Table 2. TI OTP Bank 0 Temperature Sensor Calibration Information Field Descriptions

Address	Width	Field	Description
F008 03x0h [31:16]	16 bits	SxTEMP1VAL	The value read from the ADC for this sensor at the first calibration temperature
F008 03x0h [15:0]	16 bits	SxTEMP1	The temperature in degrees Kelvin
F008 03x4h [31:16]	16 bits	SxTEMP2VAL	The value read from the ADC for this sensor at the second calibration temperature
F008 03x4h [15:0]	16 bits	SxTEMP2	The temperature in degrees Kelvin
F008 03x8h [31:16]	16 bits	SxTEMP3VAL	The value read from the ADC for this sensor at the third calibration temperature
F008 03x8h [15:0]	16 bits	SxTEMP3	The temperature in degrees Kelvin
F008 03xCh [31:16]	16 bits	0xFFFF	Reserved
F008 03xCh [15:0]	16 bits	0xFFFF	Reserved

2.4 Junction Temperature Monitor Example: Results

To estimate the accuracy of the calibrated temperature sensors, TI ran an experiment with 24 TMS570LC4357BZWT devices. The devices were in a temperature chamber where they soaked at -45°C for five minutes. Then the devices powered up and quickly did a temperature read using an ADC discharge period of 500 ns and a sample period of 1 μs . The results were returned to a PC on a CAN bus. The devices powered down and the temperature chamber incremented by one degree Celcius. The process of five minutes of soak time and then a reading repeated until the last reading was taken with the chamber at 130°C . It was important to do the ADC reading early in the code, even before the PLL initialization, to minimize the impact of the device's self heating. The results of the experiment are shown in [Figure 4](#) below. This example achieved a standard deviation of less than 2.5°C from the temperature chamber.

NOTE: The use of ambient temperatures beyond the specified operating range was done to validate the algorithms used in the calibration routines. TI does not guarantee nor imply proper operation of the parts beyond the specified operating temperature range.

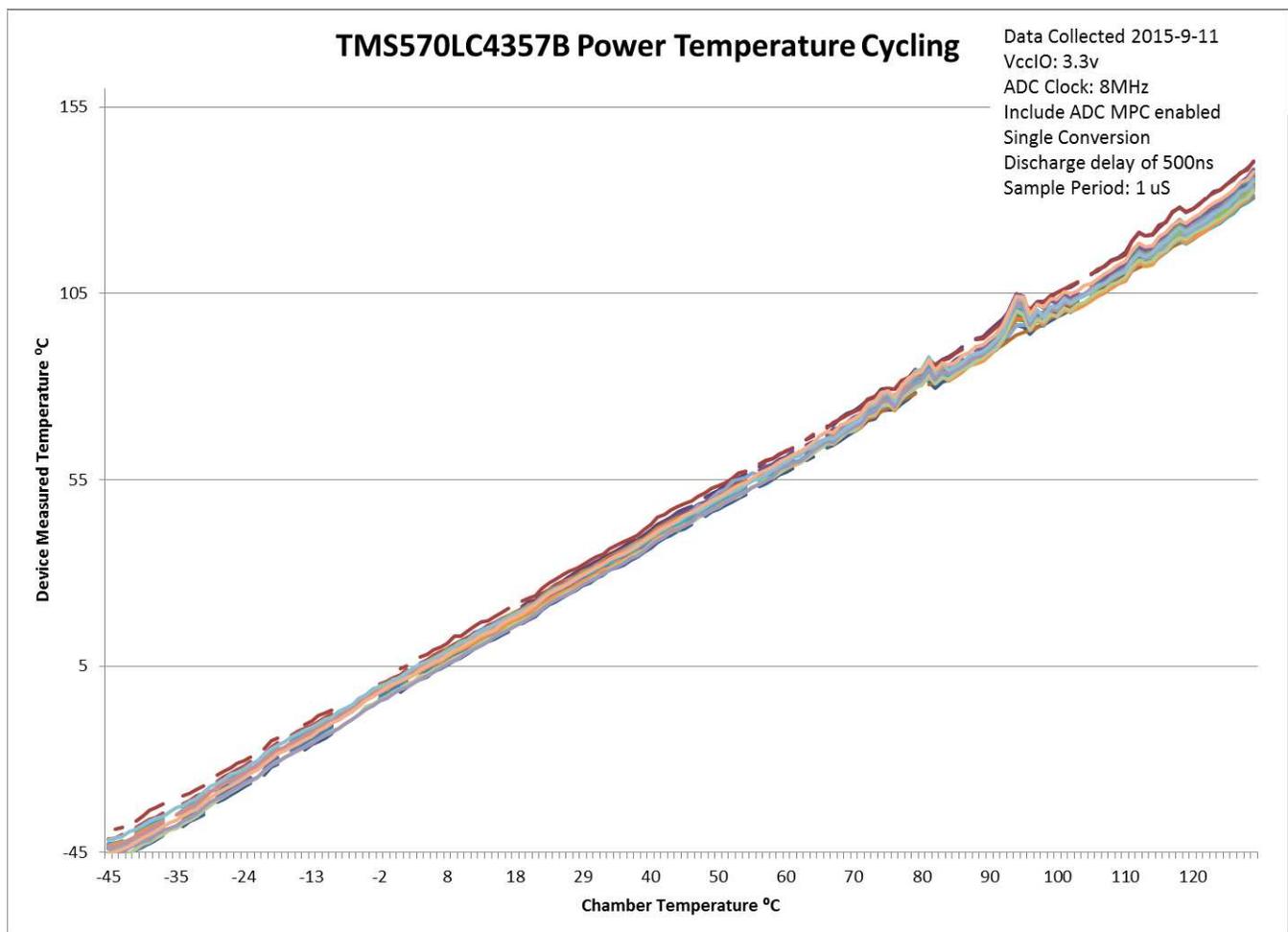


Figure 4. TMS570LC4357B Power Temperature Cycling Results

3 Example

This example is designed to demonstrate how to use the on-chip temperature sensors of the [TMS570LC4357](#) in the [TMS570LC43x launchpad](#). This example was built using [HalCoGen](#) version 04.05.01, [Code Composer Studio](#) version 6.1.1.00022 and ARM Compiler Tools version 5.2.6.

3.1 Example Code

The entire Code Composer Studio project is available in the ZIP file <http://www.ti.com/lit/zip/spna216>. All of the files were created by HalCoGen and were not hand modified except for three files. The file HL_sys_main.c was started by HalCoGen but then user code was added to create this example. The files TempSensor.h and TempSensor.c contain the code for the temperature sensor routines.

3.1.1 HL_sys_main.c

This file is provided as an example of how to call the thermistor calibration routine and the thermistor read routine. This example uses temperature sensor 3. Therefore ADC2 group one is used. The group one discharge time and sample time are set in the adclnit() routine. The 500 nS discharge time and 1 μ s sample time were setup using the HalCoGen graphical interface.

```

/* Include Files */

#include "HL_sys_common.h"

/* USER CODE BEGIN (1) */
#include "TempSensor.h"
#include "HL_adc.h"
/* USER CODE END */

/** @fn void main(void)
 * @brief Application main function
 * @note This function is empty by default.
 *
 * This function is called after startup.
 * The user can use this function to implement the application.
 */

/* USER CODE BEGIN (2) */
#define MAX_JUNCTION_TEMP 150 // Check datasheet for absolute maximum junction temperature
unsigned int ErrorCode;
float MaxTemp=0, CurrentTemp=0;
/* USER CODE END */

void main(void)
{
/* USER CODE BEGIN (3) */
float JunctionTemp, AverageTemp;
unsigned int i;

/* ADC group 1 was set to 500ns discharge and 1us sample time using HalCoGen */
/* these values are not the default values */
adcInit();
adcMidPointCalibration(adcREG2);

/* Calculate slope and intercept for sensor 3 (only need to do once) */
if(thermistor_calibration() == FALSE)
{
// Put warning about no temperature calibration data in OTP
ErrorCode = 1;
}
else
{
for(;;)
{

```

```

        if((JunctionTemp=thermistor_read()) < 0.0)
        {
            /* Put warning about failure */
            /* Return = -1; ADC2 Group 1 in use */
            /* Return = -2; Missing calibration values */
            ErrorCode = 2;
            break;
        }
        else
        {
            // Assumes ADC reference voltage is 3.30V so no scaling is required
            JunctionTemp = JunctionTemp - 273.15; // Convert from Kelvin to Celcius
            CurrentTemp = JunctionTemp; // Saving in static to make it easy to watch
            if(JunctionTemp > MAX_JUNCTION_TEMP)
            {
                // Do four readings to be sure this was not just noise on the ADC voltage
                AverageTemp = 0.0;
                for(i = 0; i < 4; i++)
                    AverageTemp += thermistor_read();
                JunctionTemp = (AverageTemp / 4.0) - 273.15;
                if(JunctionTemp > MAX_JUNCTION_TEMP)
                {
                    // Put warning "junction temperature too high" routine here
                    ErrorCode = 3;
                    break;
                }
            }
            if(JunctionTemp > MaxTemp)
                MaxTemp = JunctionTemp;
        }
    }
}

/* USER CODE END */

/* USER CODE BEGIN (4) */
/* USER CODE END */

```

3.1.2 TempSensor.h

```

#ifndef __TEMPSENSOR_H__
#define __TEMPSENSOR_H__

extern float thermistor_read(void);
extern bool thermistor_calibration(void);

#endif

```

3.1.3 TempSensor.c

```

#include "HL_sys_common.h"
#include "HL_adc.h"
#include "HL_pinmux.h"
#include "TempSensor.h"

/* Thermistor */
#ifndef __little_endian__
#define __little_endian__ 0
#endif

#if __little_endian__
typedef struct OTP_temperature_calibration_data
{
    uint16_t Temperature;
    uint16_t AdcValue;
} OTP_temperature_calibration_data_t;
#else
typedef struct OTP_temperature_calibration_data
{
    uint16_t AdcValue;
    uint16_t Temperature;
} OTP_temperature_calibration_data_t;
#endif

#define THERMISTOR_CAL_DATA          0xF0080310 /* OTP Temperature Sensor Data Location */

typedef struct Thermistor_Calibration
{
    float slope;
    float offset;
    float rsquared;
} Thermistor_CAL_t;

static Thermistor_CAL_t Thermistor_Fit = {0.0, 0.0, 0.0};

/***** Start of Temp Sensor functions *****/
/*****

/** @fn float thermistor_read(void)
 * @brief read on-chip thermistor 3
 * @note This will return the temperature of thermistor 3 in Kelvin
 *
 * This requires adcInit() to be called before to setup ADC2.
 *
 * This function will modify the Pin Muxing and ADC2 to read the thermistor,
 * care has been taken to restore modified configurations however the user is
 * responsible for verifying both the Pin Muxing and ADC are configured
 * as desired.
 *
 * The returned temperature will need to be scaled by the reference voltage difference
 * Calibration values are taken at nominal voltage 3.30V.
 *
 * Kelvin = ReturnValue * (VccADrefHi - VccADrefLow)/3.30V
 * Celsius = Kelvin - 273.15;
 * Fahrenheit = (Kelvin - 273.15) * 1.8 + 32;
 */
float thermistor_read()
{
    unsigned int value, pinmux_restore, GxSEL_restore;
    float JunctionTempK;
    adcBASE_t *adcreg;

```

```

/* Select the ADC */
adcreg = adcREG2;

if(adcreg->G1SR != 0x00000008 )
    return (-1.0); // Group 1 is being used

/* Check that we have valid calibration data */
if(Thermistor_Fit.rsquared == 0.0)
    return (-2.0); //Calibration data missing, must run thermistor_calibration() first

/* Enable Temperature Sensors in Pin Muxing */

/* Enable Pin Muxing */
pinMuxReg->KICKER0 = 0x83E70B13U;
pinMuxReg->KICKER1 = 0x95A4F1E0U;

/* Enable Temp Sensor */
pinMuxReg->PINMUX[174] &= 0xFEFFFFFF;

/* Connect Sensor 3 - Temperature sensor 3's output is connected to AD2IN[30] */
pinmux_restore = pinMuxReg->PINMUX[174];
pinMuxReg->PINMUX[174] = (pinMuxReg->PINMUX[174] & 0xffffffe) | 0x00000002;

/* Start Converting, Choose Channel */
GxSEL_restore = adcreg->GxSEL[1U]; // Save the original value in the channel select register
adcreg->GxSEL[1U] = 0x40000000;

/* Poll for end of Conversion */
while(!(adcreg->G1SR & 1));

/* Read adc value */
value = adcreg->GxBUF[1U].BUF0;

/* Disable Temperature Sensor */
pinMuxReg->PINMUX[174] |= 0x01000000;

/* Restore Sensor 3 Pin Muxing */
pinMuxReg->PINMUX[174] = pinmux_restore;

/* Disable Pin Muxing */
pinMuxReg->KICKER0 = 0x00000000U;
pinMuxReg->KICKER1 = 0x00000000U;

/* Restore Channel Select Register */
adcreg->GxSEL[1U] = GxSEL_restore;

/* Convert ADC value into floating point temp Kelvin */
JunctionTempK = (((float)value) - Thermistor_Fit.offset) *
    Thermistor_Fit.slope;

return JunctionTempK;
} // thermistor_read

/** @fn void thermistor_calibration(void)
 * @brief Load the thermister calibration information
 * @note
 */
bool thermistor_calibration(void)
{
    OTP_temperature_calibration_data_t *OTPdataptr;
    int i, cal_data_count=0;
    float slope,offset,sumtemp=0,sumconv=0,sumtempconv=0,sumtempxtemp=0;
    float cal_adc_code_array[4],avgconv,cal_temperature_array[4],yx=0.0,ya=0.0,ym,yn;

    /* Create pointer to temp sensor 3 calibration data */
    OTPdataptr = (OTP_temperature_calibration_data_t *) (THERMISTOR_CAL_DATA + (2 * 0x10));

```

```

/* Check for valid calibration data */
/* Valid codes are 0 to 0xFFF, valid temperatures are 0 to 400 kelvin */
for(i = 0; i < 4; i++)
{
    /* Calculate Slope and Offset for the 4 possible value pairs */
    if((OTPdataptr[i].AdcValue < 0xFFF) && (OTPdataptr[i].Temperature < 401))
    {
        /* Load valid calibration information */
        cal_temperature_array[i] = (float)(OTPdataptr[i].Temperature);
        cal_adc_code_array[i] = (float)OTPdataptr[i].AdcValue;
        sumtemp += cal_temperature_array[i];
        sumconv += cal_adc_code_array[i];
        sumtempxconv += cal_temperature_array[i] * cal_adc_code_array[i];
        sumtempxtemp += cal_temperature_array[i] * cal_temperature_array[i];
        cal_data_count++;
    }
}

/* Calculate slope and Offset for the 4 possible value pairs */
if(cal_data_count < 2)
    return FALSE;
else
{
    slope = (sumtempxtemp * cal_data_count - sumtemp * sumtemp) /
            (sumtempxconv * cal_data_count - sumtemp * sumconv);
    offset = (sumconv - sumtemp / slope) / cal_data_count;
    Thermistor_Fit.slope = slope;
    Thermistor_Fit.offset = offset;
    avgconv = sumconv / cal_data_count;
}

/* Calculate R-Squared Value */
for(i = 0; i < cal_data_count; i++)
{
    yn = (((cal_temperature_array[i] / slope) + offset) - cal_adc_code_array[i]);
    yx = yx + (yn * yn);
    ym = (avgconv - cal_adc_code_array[i]);
    ya = ya + (ym * ym);
}
Thermistor_Fit.rsquared = 1.0 - (yx / ya);

return TRUE;
} // thermistor_calibrate

```

4 References

- *TMS570LC43x 16/32-Bit RISC Flash Microcontroller Technical Reference Manual* ([SPNU563](#))
- *TMS570LC4357 Hercules™ Microcontroller Data Manual* ([SPNS195](#))
- *RM57L843 16/32-Bit RISC Flash Microcontroller Technical Reference Manual* ([SPNU563](#))
- *RM57L843 Hercules Microcontroller Data Manual* ([SPNS195](#))

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